

Patents and Disclosures (10)

- 1. Methods and Devices for Optical Sorting of Size-Matched Microspheres**
V.N. Astratov, provisional US patent application 61/535,409 filed on 10/14/2011.
- 2. Focusing multimodal optical microprobe devices and methods**
V. N. Astratov, International patent publication No. WO/2011/005397 (priority date 17 June 2009).
V.N. Astratov, US Patent Application Serial No. 13/321,965 filed November 22, 2011.
V.N. Astratov, European Patent Application No. 2010728058 filed January 16, 2012.
- 3. Method of Determination of Energy Parameters of High-Resistivity Electrooptic Semiconductors**
V.N. Astratov, A.V. Ilinskii, and A.S. Furman
Patent No 1833054 (In Russia), 1992
- 4. Method of Measurements of Carriers Drift Mobility in High-Resistivity Semiconductors**
V.N. Astratov, A.S. Furman, and A.V. Ilinskii
Patent No 1604099 (in Russia), 1990
- 5. Method of Measurements of Electrical Parameters of High-Resistivity Semiconductors**
V.N. Astratov, A.V. Ilinskii, and M.B. Melnikov
Patent No 1487754 (in Russia), 1989
- 6. Method of Measurements of Population of Trapping Levels in High-Resistivity Semiconductors**
V.N. Astratov, A.V. Ilinskii, and M.B. Melnikov
Patent No 1468327 (in Russia), 1988
- 7. Method of Conductivity Measurements in High-Resistivity Semiconductors**
V.N. Astratov, A.V. Ilinskii, M.B. Melnikov, S.N. Reznikov, and I.N. Hootorskoy
Patent No 1400391 (in Russia), 1988
- 8. Method of Measurements of Quantum Yield of Photo-Effect in High-Resistivity Semiconductors**
V.N. Astratov, A.V. Ilinskii, and M.B. Melnikov
Patent No 1289322 (in Russia), 1986
- 9. Method of Determination of Energy of Trapping Levels in High-Resistivity Crystals**
V.N. Astratov, A.V. Ilinskii, M.B. Melnikov, O.M. Rusakov, S.N. Reznikov, and L.N. Linnik
Patent No 1235408 (in Russia), 1986
- 10. Method of Determination of Distribution of Electric Field by Transverse Electrooptic Effect in Crystals**
V.N. Astratov, A.V. Ilinskii, L.N. Linnik, and S.N. Reznikov
Patent No 1045728 (in Russia), 1983